

ECE 538: VLSI System Testing

Assignment 4

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Duke Community Standard

By submitting this L^AT_EX document, I affirm that

1. I have adhered to the Duke Community Standard in completing this assignment.

Problem 1 Path Delay and Small Delay Defect Testing using Synopsys TetraMax:

a. Path Delay Faults

(i)

Number of Critical Paths	50	100	150	200	250	300
Total Faults	50	100	150	200	250	300
Detected	44	82	123	128	129	128
Test Coverage	88.00%	82.00%	82.00%	64.00%	51.60%	42.67%
Patterns	9	18	19	19	19	18
CPU Time	0.02	0.02	0.03	0.02	0.03	0.05

Table 1: Results for path-delay faults, 0.15ns clock period

(ii)

Number of Critical Paths	50	100	150	200	250	300
Total Faults	50	100	150	200	250	300
Detected	44	82	123	128	129	128
Test Coverage	88.00%	82.00%	82.00%	64.00%	51.60%	42.67%
Patterns	9	18	19	18	19	18
CPU Time	0.01	0.03	0.03	0.03	0.03	0.04

Table 2: Results for path-delay faults, 0.10ns clock period

b. Small Delay Defects

(i)

(ii)

(iii)

Slack	10%	15%	20%	25%	30%
Total Faults	4094	4094	4094	4094	4094
Detected	3994	3994	3994	3994	3994
Delay Effectiveness	0.11ns(55.17%)	0.165ns(30.75%)	0.22ns(50.08%)	0.275ns(49.82%)	0.33ns(53.68%)
SDQL	6289088.50	6126893.50	5438607.50	4897204.50	4477742.50
CPU Time	0.07	0.07	0.07	0.08	0.08